

**Search Notes**

Application/Control No.

10/537,470

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

YANO ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	284	3/27/2007	HN
330	124R	3/27/2007	HN
330	295	3/27/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
UW-PGPUB		7/10/2007	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	3/20/2007	HN
EAST UPDATE SEARCH	7/10/2007	HN